

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) NSC1-M3300 [P05678]	Application Number New
		Applicant(s) Charles Dark et al..	Filing Date Herewith
		Group Art Unit Unknown	

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

WL	A	"The Effects of Fluorine on Parametrics and Reliability in a 0.18-µm 3.5/6.8 nm Dual Gate Oxide CMOS Technology"; Terence B. Hook et al.; IEEE Transactions on Electron Devices, Vol. 48, No. 7, July 2001; pp 1346-1353
WL		

Examiner <i>W.L. T. Miller Jr.</i>	Date Considered <i>6/23/04</i>
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	